Learning Component Reliability with Reduced Information

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Trinity College Dublin

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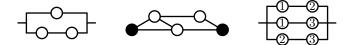


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 No Repair (Topological)
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Structural Reliability Theory

• Interest lies in the reliability of 'systems' composed of numerous 'components'.





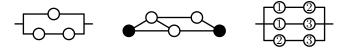


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• Interest lies in the reliability of 'systems' composed of numerous 'components'.



- Lifetime of the system, *T*, is determined by:
 - the lifetime of the components, $Y_i \sim F_Y(\cdot; \psi_i)$
 - the structure of the system.
 - the possible presence of a repair process.

via either the *structure function* or *signature*.



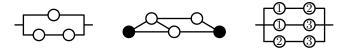


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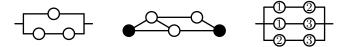


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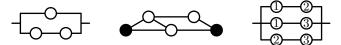


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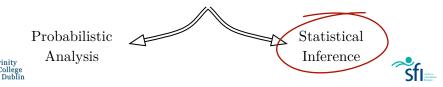
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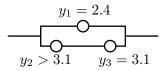
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Masked System Lifetime Data (No Repair)

Traditionally, one may have failure time data on components and then infer the parameters ψ of the lifetime distribution.

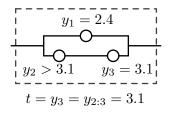






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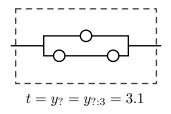
Inference a quite well understood problem here.





Masked System Lifetime Data (No Repair)

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Masked system lifetime data means only the failure time of the system as a whole is known, not the component failure times or indeed which components had failed.



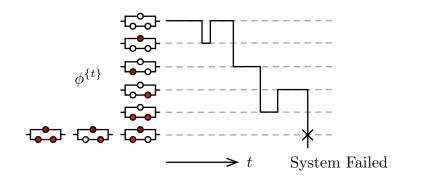


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Masked System Lifetime Data (Repair)

Traditionally, one may have full schedule of failure and repair time data on components and then infer the parameters ψ of the lifetime and repair time distributions.



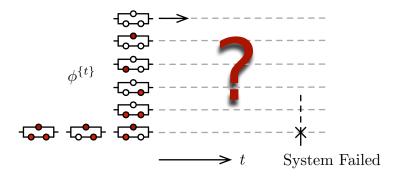




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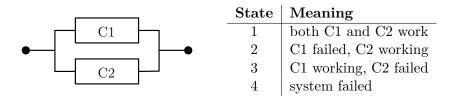


Masked system lifetime data means the schedule of failure and repair is unknown. ollege

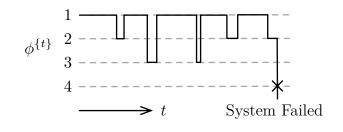
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Toy Example : Redundant Repairable Components



 \therefore a general stochastic process, e.g.

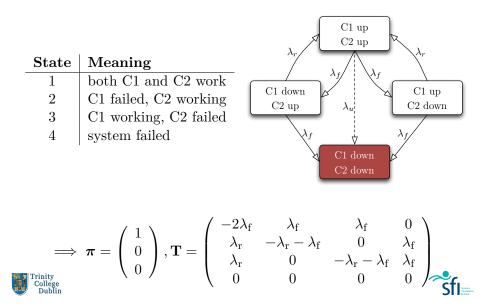






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Continuous-time Markov Chain Model for $- \begin{bmatrix} 0 \\ 0 \end{bmatrix}$



Definition of Phase-type Distributions

An absorbing continuous time Markov chain is one in which there is a state that, once entered, is never left. That is, the n+1 state generator matrix can be written:

$$\mathbf{T} = \left(\begin{array}{cc} \mathbf{S} & \mathbf{s} \\ \mathbf{0} & 0 \end{array}\right)$$

where **S** is $n \times n$, **s** is $n \times 1$ and **0** is $1 \times n$, with

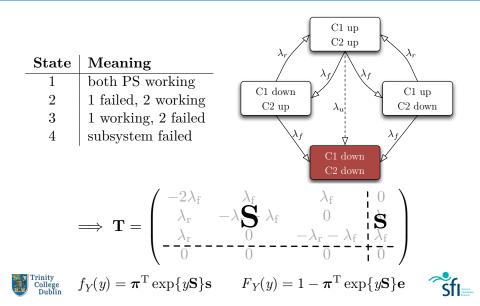
$$s = -Se$$

Then, a *Phase-type distribution* (PHT) is defined to be the distribution of the time to entering the absorbing state.

$$Y \sim \text{PHT}(\boldsymbol{\pi}, \mathbf{S}) \implies \begin{cases} F_Y(y) = 1 - \boldsymbol{\pi}^{\mathrm{T}} \exp\{y\mathbf{S}\}\mathbf{s} \\ f_Y(y) = \boldsymbol{\pi}^{\mathrm{T}} \exp\{y\mathbf{S}\}\mathbf{s} \end{cases}$$



Relating to the Toy Example



Inferential Setting

Cano *et al.* (2010) provide Bayesian learning results in the context of analysing repairable systems when the stochastic process leading to absorption is observed.

Data

For each system failure time, one has:

- Starting state
- Length of time in each state
- Number of transitions between each state
- Ultimate system failure time





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Reduced information scenario \implies Bladt *et al.* (2003) provide a Bayesian MCMC algorithm, or Asmussen *et al.* (1996) provide a frequentist EM algorithm.





Slide for Statisticians!

Strategy is a top-level Gibbs step which achieves the goal of simulating from

$$p(\boldsymbol{\pi}, \mathbf{S} \,|\, \mathbf{y})$$

by sampling from

$$p(\boldsymbol{\pi}, \mathbf{S}, \text{paths } \cdot | \mathbf{y})$$

through the iterative process

$$\left(\begin{array}{c}p(\boldsymbol{\pi},\mathbf{S} \,|\, \text{paths }\cdot,\mathbf{y})\\p(\text{paths }\cdot \,|\, \boldsymbol{\pi},\mathbf{S},\mathbf{y})\end{array}\right)$$

where $p(\text{paths } \cdot | \boldsymbol{\pi}, \mathbf{S}, \mathbf{y})$ is achieved by a rejection sampling within Metropolis-Hastings algorithm.





High-level Description of Bladt et al.

The following are key points to note about the MCMC scheme:

• fully dense rate matrix with separate parameters, e.g.

$$\mathbf{T} = \begin{pmatrix} \cdot & S_{12} & S_{13} & s_1 \\ S_{21} & \cdot & S_{23} & s_2 \\ S_{31} & S_{32} & \cdot & s_3 \\ 0 & 0 & 0 & 0 \end{pmatrix}$$

• no censored data

- slow computational speed in some common scenarios
- focused on 'distribution fitting'





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 \rightarrow we extend to allow structure to be imposed

no censored data

 \rightarrow we accommodate censoring

- slow computational speed in some common scenarios \rightarrow we provide novel sampling scheme
- focused on 'distribution fitting'

Statistical -vs- Stochastic

In other words, we adapt the MCMC algorithm to be fit for performing inference when Phase-types are used for stochastic rather than statistical modelling.

Stochastic Model \longrightarrow Aslett & Wilson

"Stochastic models seek to represent an underlying physical phenomenon of interest, albeit often in a highly idealised way, and have parameters that are physically interpretable." — Isham

Statistical Model \longrightarrow Bladt et al

"In contrast, statistical models are descriptive, and represent the statistical properties of data and their dependence on covariates, without aiming to encapsulate the physical mechanisms involved." — Isham



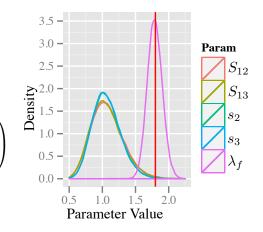




Toy Example Results

100 uncensored observations simulated from PHT with

$$\mathbf{S} = \begin{pmatrix} -3.6 & 1.8 & 1.8 \\ 9.5 & -11.3 & 0 \\ 9.5 & 0 & -11.3 \end{pmatrix}$$
$$\implies \lambda_f = 1.8, \ \lambda_r = 9.5$$





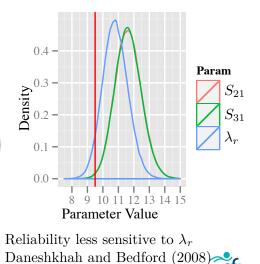




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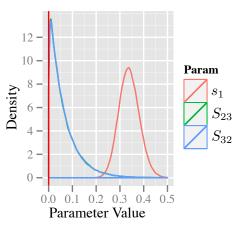




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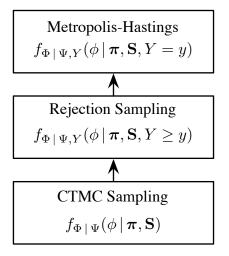
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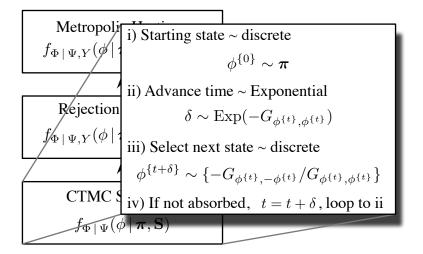
Solution: "Exact Conditional Sampling"







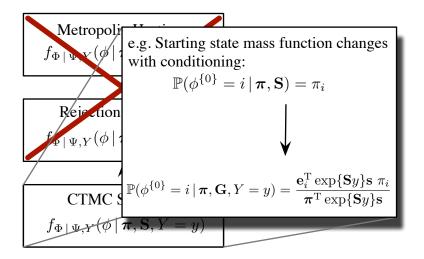
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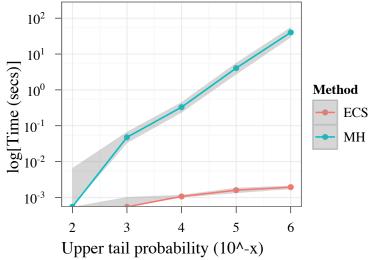
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'Tail Depth' Performance Improvement







Overall Performance Improvement

This shows the new method keeping pace in 'nice' problems and significantly outperforming otherwise.

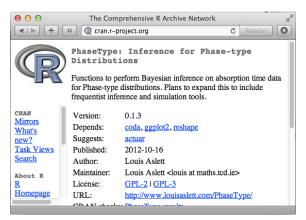
$\mathbf{T} = \begin{pmatrix} -3 & 1 & 1 & 1 \\ 1 & -3 & 1 & 1 \\ 1 & 1 & -3 & 1 \\ 0 & 0 & 0 & 0 \end{pmatrix}$	$\mathbf{T} = \begin{pmatrix} -2 & 0.01 & 1.99 & 0\\ 1 & -300 & 0 & 299\\ 299 & 0 & -300 & 1\\ 0 & 0 & 0 & 0 \end{pmatrix}$		
<u>No</u> problems i-iii	<u>All</u> problems i-iii		
MH ECS	MH ECS		
\bar{t} 1.6 7.2	10.2 hours 0.016 secs		
s_t 104 19	9.4 hours 0.015 secs		

 $2,300,000 \times \text{faster on average in hard problem}$





R Package: PhaseType



http://cran.r-project.org/package=PhaseType





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Again, the missing data is what makes the inference hard. Tanner and Wong (1987) is a classic solution to this in a Bayesian framework if the missing data can be simulated. Consider the system --- from the introduction, with observed system failure times:

$$\mathbf{t} = \{1.1, 4.2\}$$

$$\psi = \psi_1$$

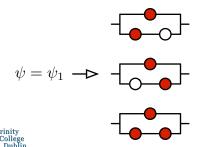






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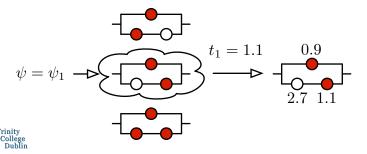
 $\mathbf{t} = \{1.1, 4.2\}$







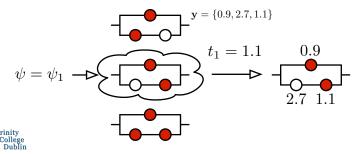
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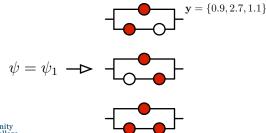






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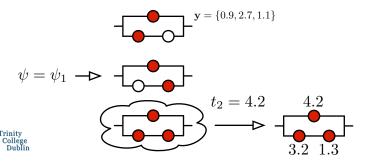








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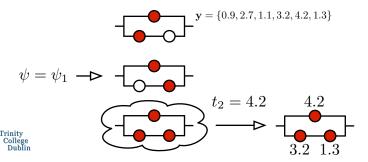




Missing Data

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Need realisations concordant with each observation:





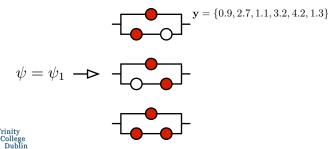


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$$\mathbf{t} = \{1.1, 4.2\}$$

Need realisations concordant with each observation:

$$\psi = \psi_2$$





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Missing Data

For any statisticians, that is:

$$\left(\begin{array}{c}f_{Y\,|\,\Psi,T}(\mathbf{y}_{1\cdot},\ldots,\mathbf{y}_{m\cdot}\,|\,\psi,\mathbf{t})\\\\f_{\Psi\,|\,Y,T}(\psi\,|\,\mathbf{y}_{1\cdot},\ldots,\mathbf{y}_{m\cdot},\mathbf{t})\end{array}\right)$$





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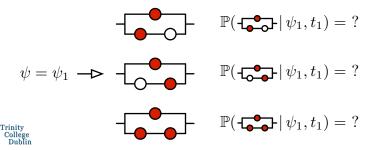
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What is the challenge?





System Signatures

The signature (Samaniego, 1985) is less widely used than the structure function, but in some ways more elegant.

Definition (Signature)

The signature of a system is the *n*-dimensional probability vector $\mathbf{s} = (s_1, \ldots, s_n)$ with elements:

$$s_i = \mathbb{P}(T = Y_{i:n})$$

where T is the failure time of the system and $Y_{i:n}$ is the *i*th order statistic of the *n* component failure times.





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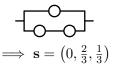
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e.g.







Sampling Latent Failure Times

It can be shown:

$$f_{Y|T}(y_{i1}, \dots, y_{in}; \psi \mid t)$$

$$\propto \sum_{j=1}^{n} \left[f_{Y|Y < t}(y_{i(1)}, \dots, y_{i(j-1)}; \psi) \right]$$

$$\times f_{Y|Y>t}(y_{i(j+1)},\ldots,y_{i(n)};\psi)$$

$$\times \mathbb{I}_{\{t\}}(y_{i(j)})$$

$$\times \binom{n-1}{j-1} F_Y(t;\psi)^j \overline{F}_Y(t;\psi)^{n-j+1} s_j \Big]$$





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Signature based data augmentation

1 With probability

$$\mathbb{P}(j) \propto \binom{n-1}{j-1} F_Y(t_i; \psi)^j \bar{F}_Y(t_i; \psi)^{n-j+1} s_j$$

it was the *j*th failure that caused system failure.

- **2** Having drawn a random j, sample
 - j-1 values, $y_{i1}, \ldots, y_{i(j-1)}$, from $F_{Y|Y < t_i}(\cdot; \psi)$, the distribution of the component lifetime conditional on failure before t_i
 - n-j values, $y_{i(j+1)}, \ldots, y_{in}$, from $F_{Y|Y>t_i}(\cdot; \psi)$, the distribution of the component lifetime conditional on failure after t_i

and set $y_{ij} = t_i$.





Prerequisites

This is a very general method. The prerequisites for use are,

- 1 The signature of the system;
- The ability to perform standard Bayesian inference with the full data;
- **3** The ability to sample from $F_{Y|Y < t_i}(\cdot; \psi)$ and $F_{Y|Y > t_i}(\cdot; \psi)$.





Prerequisites

This is a very general method. The prerequisites for use are,

1 The signature of the system;

Easy for systems that are not huge

 The ability to perform standard Bayesian inference with the full data;

Easy for common lifetime distributions

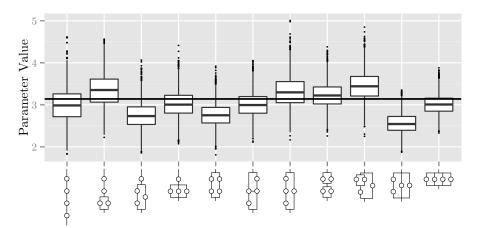
3 The ability to sample from $F_{Y|Y < t_i}(\cdot; \psi)$ and $F_{Y|Y > t_i}(\cdot; \psi)$.

Depends!





Canonical Exponential Component Lifetime Example

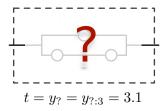






Unknown Topologies

A little 'blue skies' academic thinking ...







Uniqueness of the Signature

		Signature repetition							
Type	Order	Unique	2	3	4	5	6	7	Total
	2	2	0	0	0	0	0	0	2
Coherent	3	5	0	0	0	0	0	0	5
systems	4	14	3	0	0	0	0	0	20
	5	43	15	2	6	2	10	1	180
	2	2	0	0	0	0	0	0	2
Coherent	3	4	0	0	0	0	0	0	4
systems	4	11	0	0	0	0	0	0	11
/w graph	5	27	4	0	0	0	0	0	35





Signature & Topology

Order 4 coherent systems with graph representation.

System Topology	Signature	System Topology	Signature
	(1, 0, 0, 0)	-CHC-	$\left(0, \frac{1}{3}, \frac{2}{3}, 0\right)$
	$\left(\tfrac{1}{2}, \tfrac{1}{2}, 0, 0\right)$		$\left(0, \frac{1}{2}, \frac{1}{4}, \frac{1}{4}\right)$
$- \circ [\stackrel{\circ}{\longrightarrow}]$	$\left(\tfrac{1}{4}, \tfrac{7}{12}, \tfrac{1}{6}, 0\right)$	-{6}-0-	$\left(0, \frac{1}{6}, \frac{7}{12}, \frac{1}{4}\right)$
	$\left(\frac{1}{4},\frac{1}{4},\frac{1}{2},0\right)$		$\left(0,0,\frac{1}{2},\frac{1}{2}\right)$
-0-0-	$\left(0, \frac{2}{3}, \frac{1}{3}, 0\right)$	jêj	(0, 0, 0, 1)
-[$\left(0, \frac{1}{2}, \frac{1}{2}, 0\right)$	to-	





Jointly Inferring the Topology

$$\left\langle \begin{array}{c} f_{Y \mid \Psi, T}(\mathbf{y}_{1}, \dots, \mathbf{y}_{m}, \mid \psi, \mathbf{t}) \\ \\ f_{\Psi \mid Y, T}(\psi \mid \mathbf{y}_{1}, \dots, \mathbf{y}_{m}, \mathbf{t}) \end{array} \right\rangle$$





Jointly Inferring the Topology

$$\left\langle \begin{array}{c} f_{Y \mid \Psi, T}(\mathbf{y}_{1}, \dots, \mathbf{y}_{m}, \mid \psi, \mathbf{t}, \mathbf{s}) \\ \\ f_{\Psi \mid Y, T}(\psi \mid \mathbf{y}_{1}, \dots, \mathbf{y}_{m}, \mathbf{t}, \mathbf{s}) \end{array} \right\rangle$$





Jointly Inferring the Topology

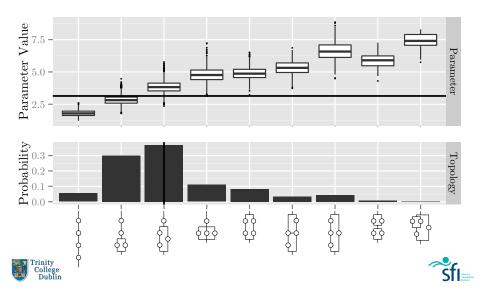
$$\left\langle \begin{array}{c} f_{Y \mid \Psi, T}(\mathbf{y}_{1}, \dots, \mathbf{y}_{m}, \mid \psi, \mathbf{t}, \mathbf{s}) \\ \\ f_{\Psi \mid Y, T}(\psi \mid \mathbf{y}_{1}, \dots, \mathbf{y}_{m}, \mathbf{t}, \mathbf{s}) \end{array} \right\rangle$$

After satisfying a few technical subtleties, implementation is not too difficult.

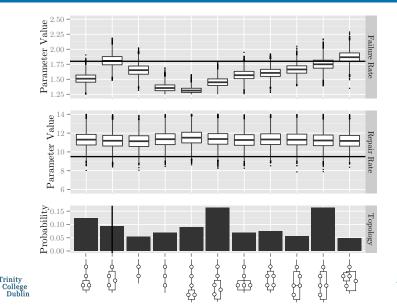




Canonical Exponential Component Lifetime Example



Phase-type Component Lifetime Example

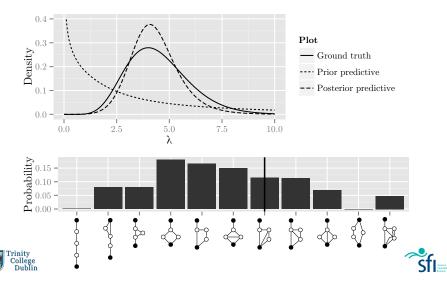






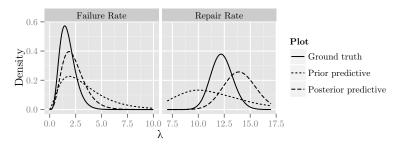
Exchangeable Systems

The i.i.d. systems assumption easily relaxed to exchangeability.



Phase-type Component Lifetimes

Extreme generality of the solution allows wide variety of component lifetime distributions. Solutions to the prerequisites have been derived for Phase-type distributed components.



May interpret as:

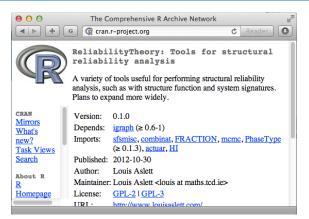
• Repairable redundant subsystems;



• Theoretically dense in function space of all positively ¹⁶/_{lin} supported continuous distributions.



R Package: ReliabilityTheory



http://cran.r-project.org/package=ReliabilityTheory





Future Work

A couple of the many important avenues to be pursued:

- Many partial information scenarios between full information and the extreme presented here.
- Extend the non-repairable work to non-identical components using the survival signature (Coolen and Coolen-Maturi, 2012).





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